

# SUSS MicroTec's Asia Seminar Series 2007, Shanghai

Date : 22<sup>nd</sup> Oct 2007

Venue : River Front Business Hotel

上海龙东商务酒店

**SUSS** MicroTec

Co-Hosts

**ProPlus**  
DESIGN SOLUTIONS INC

**KEITHLEY**

**Anritsu**

## STREAMLINING THE DEVELOPMENT CYCLE

- Using Advanced Wafer-level Test Techniques  
to Overcome Today's Challenges

Time	Synopsis	Speaker
0900hr – 0930hr :	Seminar Registration	
0930hr – 0945hr :	Opening Speech	Li GONG SUSS MicroTec
0945hr – 1030hr :	SUSS' MicroTec's Innovative ProbeShield Technology - the foundation for accurate on-wafer device characterization	Andrej RUMIANTSEV SUSS MicroTec
1030hr – 1045hr :	-- Tea Break --	
1045hr – 1130hr :	Flicker Noise & WLR Modeling Solutions	YANG Lian Feng ProPlus Design Solutions
1130hr – 1215hr :	Accurate Impedance Characterization - Getting the best out of your test equipment	Andrej RUMIANTSEV SUSS MicroTec
1215hr – 1315hr :	-- Lunch --	
1315hr – 1400hr :	Multiport Balanced Differential Measurements	XU Zhi Anritsu
1400hr – 1445hr :	Addressing the Trend Towards Long-term, Wafer-level Reliability Measurements	Stojan KANEV SUSS MicroTec
1445hr – 1500hr :	-- Tea Break --	
1500hr – 1545hr :	New Reliability Challenges and Solution / Pulsed IV Applications	Joey GU Keithley Instruments



The Next Generation of On-wafer Probing Architecture

Register by 15 Oct 2007 :  
Email : [c.sun@suss.com.cn](mailto:c.sun@suss.com.cn)

## Biographies

### **Stojan KANEV**

*Director of Marketing  
SUSS MicroTec*



Stojan holds a Ph.D. in Electronic & Electrical Engineering from the Technical University in Dresden (Germany). He joined SUSS MicroTec in 1995 within the Test Division's product management group and has held various positions since. After launching the ProbeShield technology products in 1996, he quickly moved into the sales organization and eventually became manager of the direct sales channel covering strategic regions of Europe. Since 2005 Stojan has held the World Wide Director of Marketing position for the Test System Division.

### **Andrej RUMIANTSEV**

*Application Manager  
SUSS MicroTec*



Andrej was born in Minsk, Belarus in 1972. He received the Diploma-Engineer degree (with highest honors) in telecommunication systems and the Research-Engineer degree in electrical engineering from the Belarusian State University of Informatics and Radio Electronics in Minsk, Belarus. Andrej joined SUSS MicroTec's Test Systems Division in Dresden as a RF & Microwave Application Specialist, and currently as the Application Group Manager. His current research interests include calibration and wafer-level measurement techniques for new generation RF and Microwave semiconductor devices.

### **Joey GU**

*Application Engineer  
Keithley Instruments Inc.*



MR Gu, after graduated from Shanghai JiaoTong University as a BS with focus on instrument engineering, has been working as an application engineer of the wafer level parametric testing for more than 3 years. Joined Keithley in the spring of 2006, now taking charge in the service and application for the parametric tester (S680, S500, 4200) and the SourceMeter Product Line. His major area of focus is the application of Keithley's instrument for the new measurement challenge in the semiconductor industry and integrating system-level solution for the emerging measurement needs.

### **YANG Lian Feng**

*General Manager  
ProPlus Design Solutions, Inc*



Dr Yang is the General Manager of the Beijing R&D Center. Prior to joining ProPlus, Dr. Yang was a Senior Product Engineer for the Advanced Device Modeling product line at Cadence. He co-founded one company focused on IC design in 1999. Dr. Yang earned his Ph.D. degree in E.E. from University of Glasgow, UK, and has published ~40 technical papers in international conferences and journals.

### **XU Zhi**

*Assistant Director of Marketing  
Anritsu*



Xu Zhi has more than 20 years experience in the test and measurement industry. Over the years, he has gained in-depth experience in microwave technologies and measurement techniques.